



# Grain boundary character distribution in electroplated nanotwinned copper

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## ABSTRACT

The grain boundary character distribution (GBCD) of nanotwinned copper, fabricated by electroplating inside small-scale through-wafer vias, was characterized using a stereological interpretation of electron backscatter diffraction maps. The GBCD of electroplated nanotwinned copper, specified by five macroscopic parameters (three for the lattice misorientation and two for the grain boundary plane inclination), is similar to the GBCD of coarse-grained polycrystalline copper used here as a reference material. The GBCD was compared to calculated grain boundary energies determined from atomistic simulations. We find that the grain boundary population in the electroplated nanotwinned and coarse-grained reference copper is both on average inversely correlated to the grain boundary energies. The slopes of the relationships between grain boundary population and energy for the most highly populated misorientations ( $\Sigma 3$ ,  $\Sigma 9$ , and  $\Sigma 11$ ) are different. The relationships are strongly influenced by the geometric constraints at the triple junctions and multiple twinning, which enhanced the observed frequencies of  $\Sigma 9$  boundaries. The results suggest that the grain boundary network and the GBCD in the polycrystalline specimens are strongly influenced by the microstructure, grain boundary energy, and multiple twinning.

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## Introduction

Most solid materials are polycrystalline, meaning that they consist of multiple crystals (grains) and a network of internal interfaces where the grains abut (grain boundaries). The geometric structure of the grain boundary is crystallographically defined by five macroscopic degrees of freedom (three for a lattice misorientation and two for a grain boundary plane orientation [1–3]). It has been well established that increasing the population of special boundaries can significantly affect and actually improve a wide range of material properties [4, 5]. For example, mechanical strength, electrical conductivity, segregation, damage, and corrosion resistance are strongly correlated to the fraction of special grain boundaries in polycrystalline materials [4–16]. These special grain boundaries, which are often characterized by superior properties compared to average boundaries, have low energies and are terminated by at least one low index plane [16–21]. Processing methods used to increase and utilize the occurrence of special grain boundaries are referred to as Grain Boundary Engineering (GBE) [21–26].

The most common practice is to use thermo-mechanical processing to enhance the frequency of  $\Sigma 3$  boundaries in polycrystalline materials [13, 25–34]. This technique can only be used for coarse-grained polycrystalline materials due to the substantial grain growth during thermal annealing. Recently, it was reported that nanotwinned polycrystalline copper synthesized by electroplating [8, 9, 35–37] and magnetron sputtering techniques [10, 38] exhibits high hardness, high resistance to electromigration, and yet normal electrical conductivity comparable to that of pure copper. These observations represent a paradigm shift for grain boundary engineering (GBE), making it possible to tailor nano-polycrystalline materials with an increased fraction of desired grain boundaries. Nevertheless, only a few studies investigated the grain boundary character distribution (GBCD) of nanotwinned copper [8, 9]. Previous studies examined the microstructure of nanotwinned copper using transmission electron microscopy (TEM) [8–10, 39]; however, the results of these studies do not provide enough data to quantify the population distribution of grain boundaries over all five parameters. Therefore, the objective of the present study is to investigate the GBCD in nanotwinned copper using electron backscatter diffraction (EBSD), which has a wider field of view than TEM [39–42].

A second objective of the study is to compare the GBCD of nanotwinned copper to the GBCD of coarse-grained reference copper. In coarse-grained polycrystalline materials, it is known that grain boundary populations are, on average, inversely correlated to the grain boundary energy distribution (GBED) [43–48]. While the grain boundary population in nanocrystalline tungsten is also inversely correlated to the grain boundary energy [49, 50], this may or may not be true for electroplated nanotwinned copper. The relationship between the GBCD and GBED is thought to be established during grain growth [51, 52], and nanostructured materials formed by electroplating undergo much less grain growth than in a coarse-grained material. Whether or not sufficient grain growth occurs in a nanocrystalline material to establish the same GBCD as a coarse-grained microstructure with the same chemical composition is not known. Therefore, the main purpose of the present study is to determine whether or not the GBCD of electroplated nanotwinned copper is inversely correlated to the GBED. We therefore compare the GBCD of electroplated nanotwinned copper to the GBCD of high-purity coarse-grained copper, and grain boundary energies extrapolated from simulated grain boundary energies [53] using the function established by Bulatov et al. [54]. It is expected that the relationships between grain boundary structure, energy, and population in nanotwinned copper will lead to a better understanding of the formation mechanism of coherent twin boundaries in nanotwinned copper.

## Experimental procedures

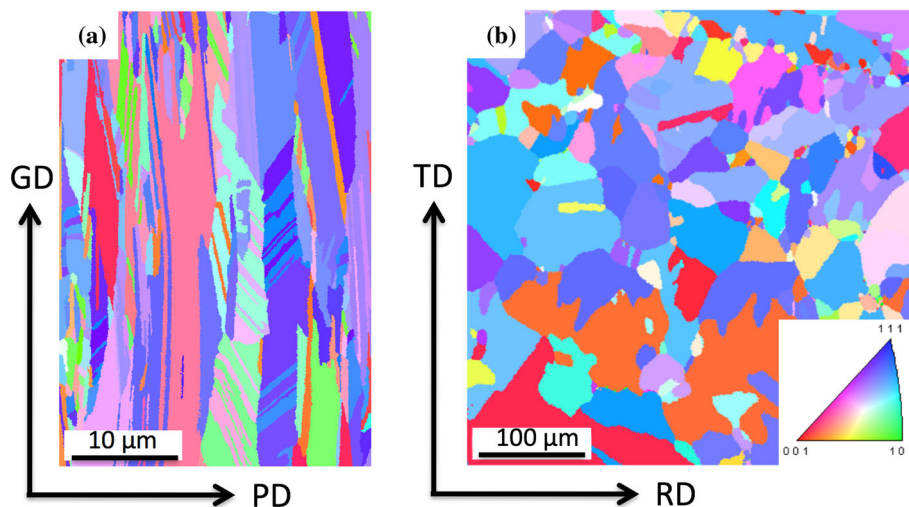
The nanotwinned copper was plated from a copper electrolyte composed of copper sulfate, sulfuric acid, hydrochloric acid, and organic additives (ATOTECH, Germany) [55]. The plating conditions are similar to a pulsed plating condition with a pulse on-time of 20 ms and a pulse off-time of 1 ms. However, to deposit copper into high-aspect ratio through-wafer vias with a diameter of 100  $\mu\text{m}$ , the current densities and pulse conditions were varied with thickness. Specifically, low forward current densities (10–25  $\text{mA}/\text{cm}^2$ ) and high reverse current density (65–45  $\text{mA}/\text{cm}^2$ ) were used during the pulse on- and off-times, respectively [9]. The details of the electroplating technique were reported elsewhere [9, 55].

The coarse-grained copper specimens were prepared from cold rolled copper sheets, Alfa Aesar Puratronic (99.9999%), which were annealed in a hydrogen flow furnace at 300 °C for 2 h. The surfaces of the coarse-grained copper were prepared by grinding with SiC papers (400, 600, 800, and 1200 grits), polishing with a diamond paste (3  $\mu\text{m}$ ), and fine polishing with colloid silica (40 nm). For the nanotwinned copper samples, surface deformation from mechanical polishing was removed by argon ion milling (Gatan 1682, 2 keV for 15 min).

The crystal orientations of the copper specimens were characterized using a high-resolution field emission scanning electron microscope equipped with an electron backscatter diffraction (EBSD) detector. The specimens were tilted at an angle of 70°. The measurements were carried out using a 15 keV electron beam and a working distance of 15 mm. Regular hexagonal grids with a step size of 100 nm and 1  $\mu\text{m}$  were used for the nanotwinned copper and coarse-grained copper, respectively. To remove misindexed data from the measurement, the crystal orientation maps were processed by standard clean-up routines using the TSL OIM software. The raw data were first processed using a neighbor confidence index (CI) correction, in which the crystal orientation and the CI of all pixels with  $\text{CI} < 0.1$  were changed to the ones of the neighbor pixels having the highest CI. The confidence indices of all points in a grain were

then changed to the highest CI found in the grain using a grain CI standardization. The data were subsequently processed with grain dilation using a single step with a minimum grain size of 50 pixels and a tolerance angle of 5°. Finally, the crystallographic orientation of the grain was determined from the average orientation of all pixels within the grain. The reconstructed grain boundary line segments used for the stereological GBCD calculation were extracted from the processed EBSD maps. When line segments deviated from the grain boundary plane were more than two pixels, the segments were divided to obtain a better match with the curvatures of grain boundaries [56]. The GBCDs of nanotwinned and coarse-grained copper were calculated from 51,771 and 51,777 line segments using the stereological method with a texture correction scheme and a binning resolution of 10° [1, 2, 6]. The technique is described in detail elsewhere [57]. The GBCDs are measured in multiples of a random distribution (MRD). Values greater than one indicate that the boundaries are observed more frequently than expected in a random distribution.

To investigate the relationship between grain boundary population and energy, we compare the grain boundary population to the grain boundary energy of copper derived from the grain boundary energy function for FCC metals proposed by Bulatov et al. [54]. The function provides a method of



**Figure 1** EBSD maps of the electroplated nanotwinned copper (a) and coarse-grained copper (b). The inset in b indicates the crystallographic vectors used to color orientations in the maps. The electroplated nanotwinned image is colored with reference to growth direction (GD) and in plane direction (PD). For the coarse-

grained copper, the rolling direction (RD) is perpendicular to transverse direction (TD) and normal direction (ND). Note that the scale bar in the nanotwinned copper is ten times smaller than that in the coarse-grained copper. These are representative subsets of all the data.

extrapolating between known points established by embedded-atom method simulations [53]. In this study, we use a catalog of the 39777 grain boundaries that can be constructed in a periodic cell with dimensions less than or equal to  $55a_0/2$ , where  $a_0$  is the lattice spacing [58]. The construction of these grain boundaries was described in references [53, 59]. This catalog has 1058 different misorientations, and the largest  $\Sigma$  in the dataset is 34075. These boundaries are not evenly distributed across the five macroscopic degrees of freedom. There are 1429  $\Sigma 3$ , 934  $\Sigma 5$ , 611  $\Sigma 7$ , 984  $\Sigma 9$ , and 445  $\Sigma 11$  boundaries.

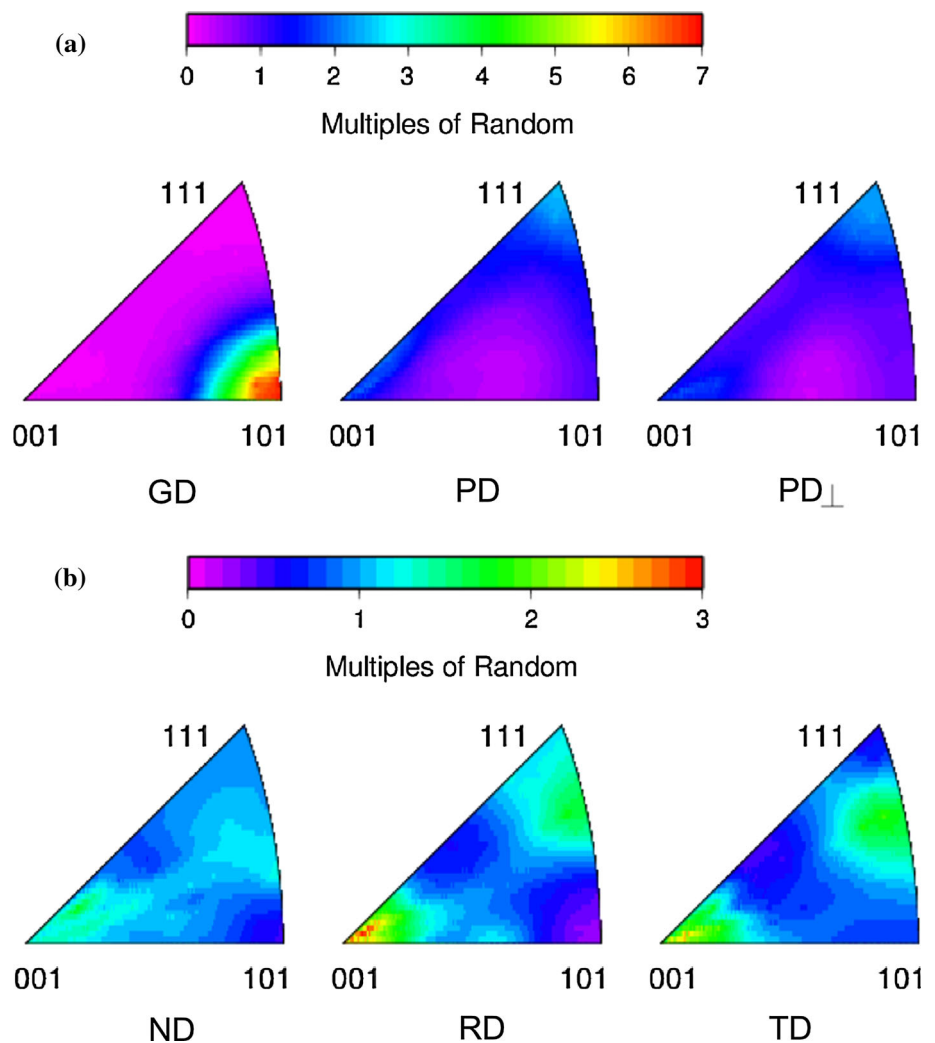
### Results

Representative EBSD maps of the specimens are shown in Fig. 1. There are multiple nanotwinned lamellae, which are elongated parallel to each other

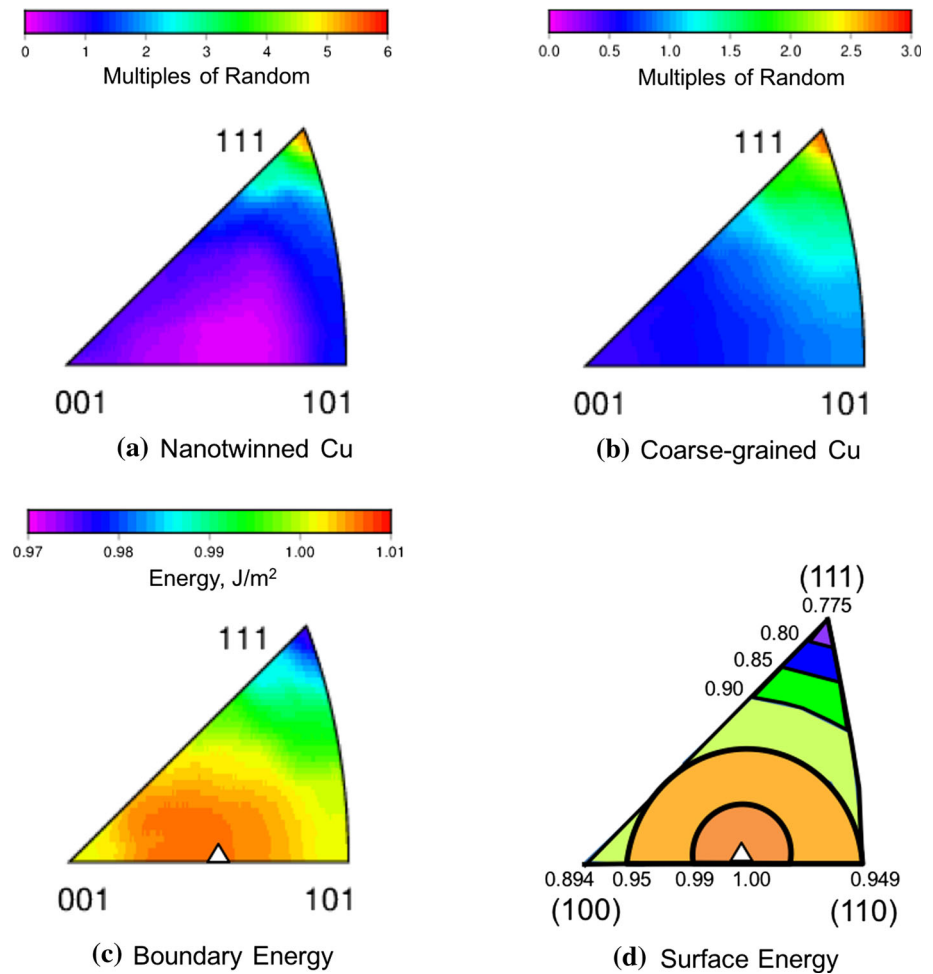
in the parental grain in the electroplated copper specimen as illustrated in Fig. 1a. The coarse-grained copper in Fig. 1b has equiaxed grains with curved boundaries. The sizes of the grains in the coarse-grained copper are much larger than those in the electroplated nanotwinned copper. The electroplated nanotwinned copper has a strong [110] fiber texture parallel to the growth direction as shown in Fig. 2a. The coarse-grained copper in Fig. 2b has (001) [100] cube texture, which is consistent with the annealing texture of cold rolled copper foils [60, 61]. The relative areas for grain boundary planes for all misorientations of the specimens are shown in the grain boundary plane distributions (GBPD) in Fig. 3. The GBPD of the electroplated nanotwinned copper (Fig. 3a) is similar to what is observed in the coarse-grained copper (Fig. 3b).

While the maxima in the grain boundary plane distributions for electroplated nanotwinned (Fig. 3a)

**Figure 2** Inverse pole figures for the electroplated nanotwinned copper (a) and coarse-grained copper (b). The frequency of the crystallographic texture components is specified in units of multiples of a random distribution (MRD). Nanotwinned copper has a strong [101] fiber texture parallel to the growth direction (GD). Note that  $PD_{\perp}$  is the sample reference direction that is perpendicular to the [101] growth direction (GD) and in plane direction (PD). The distributions of coarse-grained copper are plotted with the reference direction parallel to the normal direction (ND), rolling direction (RD), and transverse direction (TD) of the sample.



**Figure 3** Grain boundary plane distributions (GBPD) calculated without considering the misorientation in the electroplated nanotwinned copper (a) and coarse-grained copper (b). The frequencies of the observed grain boundary planes are specified in the units of multiples of a random (MRD). The distribution of grain boundary energy in copper (c) is similar to the distribution of surface energy (d) calculated from the nearest neighbor broken bond model for FCC metals, reproduced from Ref. [62]. The units for energy are scaled with  $E(210) = 1.00$  (energy maximum) represented as a triangle in the figure.



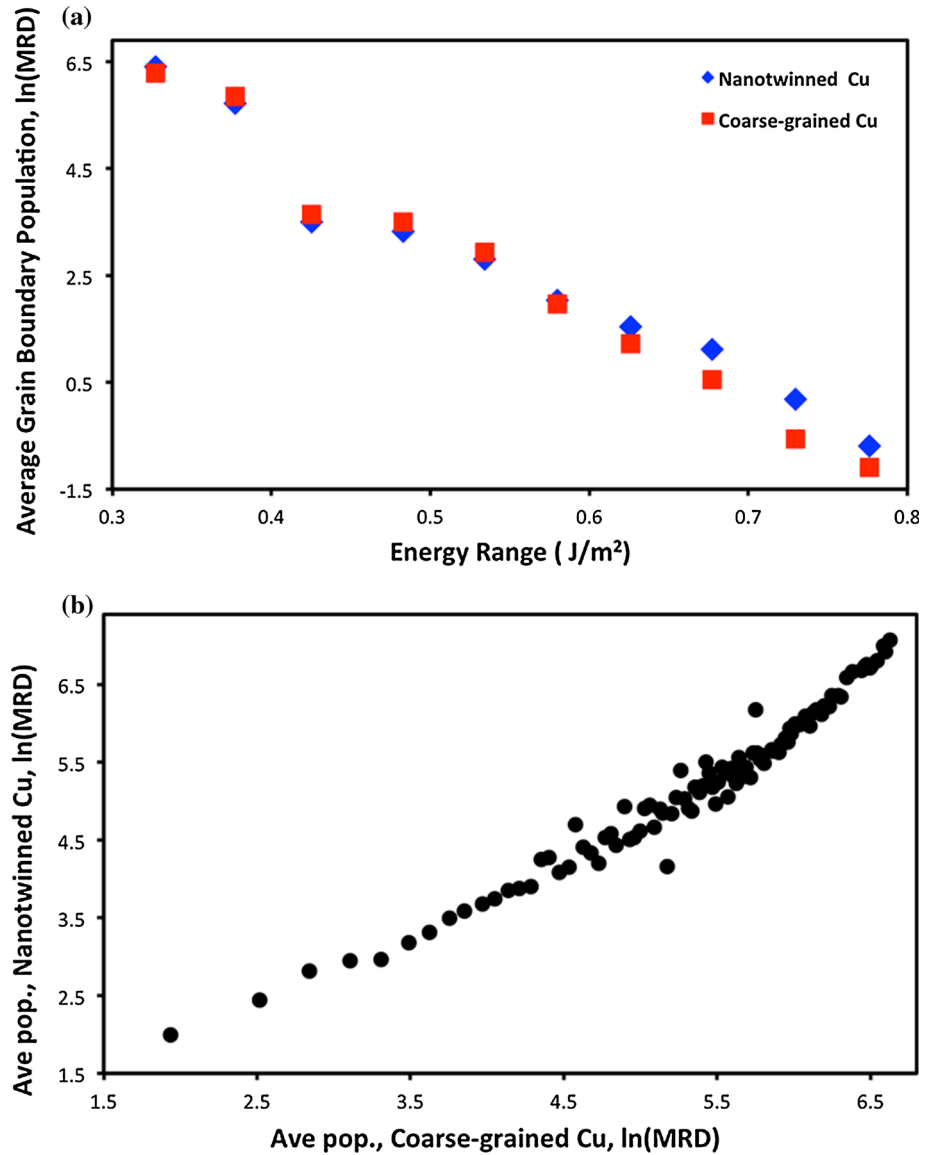
and coarse-grained copper (Fig. 3b) are both centered at the (111) position, the maximum in the nanotwinned copper (6.0 MRD) is much greater than that in the coarse-grained copper (2.9 MRD). The GBPD in the nanotwinned copper has its minimum (0.1 MRD) at the (210) position. The relative area for the (210) grain boundary plane in the coarse-grained copper (0.7 MRD) is slightly larger than the actual minimum value (0.5 MRD) at (001) position in Fig. 3b. The grain boundary energy distribution for copper, derived from the energies of 39777 grain boundaries extrapolated from the boundary energy function [54], is shown in Fig. 3c. The distribution is similar to the measured boundary energies in the FCC metals (nickel [44] and austenitic steel [48]) and the distribution of surface energy calculated from the nearest-neighbor broken-bond model (Fig. 3d) [62]. While the broken-bond model is not expected to be quantitatively accurate, it agrees well with the experimental results [63] and the results obtained from molecular

dynamics simulations conducted in conjunction with an embedded-atom potential model [64]. The minimum and the maximum values in the grain boundary energy functions are similar to the distribution of the surface energy [62–64], which has the minimum and maximum at (111) and (210), respectively. This result implies that the energy of a grain boundary in Fig. 3c is correlated to the energy of the surfaces in Fig. 3d that makes up the grain boundary [4, 65].

The results of the average relationships between the grain boundary populations and the grain boundary energies are plotted in Fig. 4a. The grain boundary energies in copper are sorted into equal bins with 0.05 J/m<sup>2</sup> intervals. The average values of grain boundary energy in each bin are calculated, and the average populations for all grain boundaries in a given bin are then calculated. The analysis demonstrates that the grain boundary populations in the electroplated nanotwinned copper and in the coarse-grained copper are on the average correlated



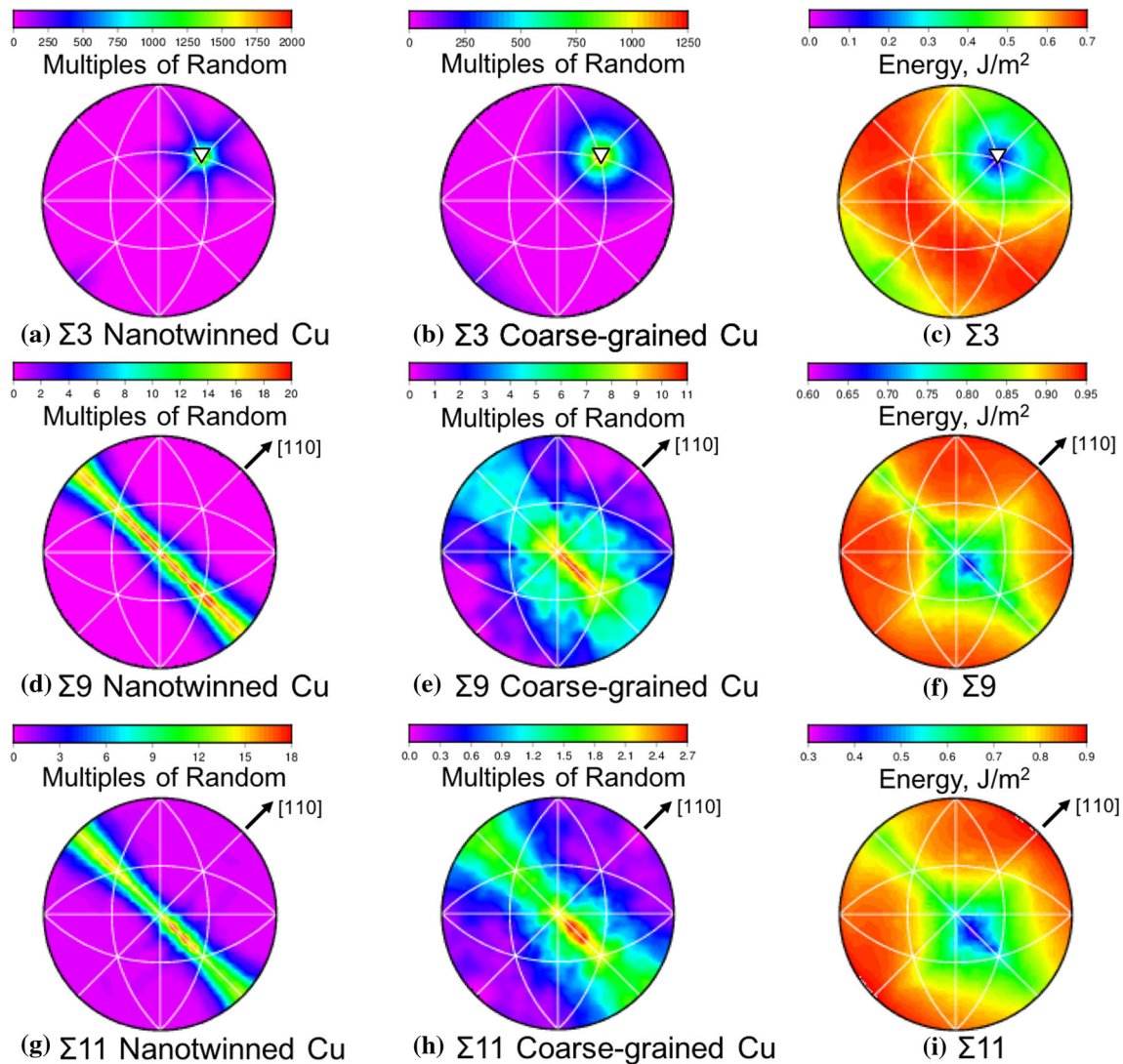
**Figure 4** Average relationships between grain boundary populations and energies in the electroplated nanotwinned and the reference coarse-grained copper specimens (a). Comparison of average population (Ave pop.) in the electroplated nanotwinned and coarse-grained copper is shown in b. The populations and energies are classified into equally spaced bins with a width of 5 MRD and 0.05 J/m<sup>2</sup> respectively. Note that the populations are plotted using a logarithmic scale.



inversely to the grain boundary energy, which is consistent with the previously observed correlation in polycrystalline materials [43–48, 66]. The comparison between the average grain boundary populations in the two types of copper specimens is shown in Fig. 4b. The grain boundary populations in the coarse-grained copper are sorted into equal bins with an interval of 5 MRD; the average populations for the same grain boundaries in the electroplated nanotwinned copper are then calculated and used as the vertical coordinate. This result indicates a strong correlation and also suggests that, on average, the grain boundary population distributions in the

copper specimens are mainly controlled by the grain boundary energy and that even in the electroplated specimen, there was enough grain growth to reach the same distribution as the coarse-grained specimen.

The fractional interface lengths, quantified using Brandon’s criterion [67], for the  $\Sigma 3$ ,  $\Sigma 9$ ,  $\Sigma 11$ ,  $\Sigma 27a$ , and  $\Sigma 27b$  boundaries are 54% (60%), 0.9% (2.9%), 0.9% (0.11%), 0.2% (0.5%), and 0.01% (0.3%), respectively, in the electroplated nanotwinned copper (coarse-grained copper). While the fraction of all  $\Sigma 3$  boundaries in the electroplated nanotwinned copper (54%) is slightly lower than that in the coarse-grained copper (60%), the fraction of coherent twin



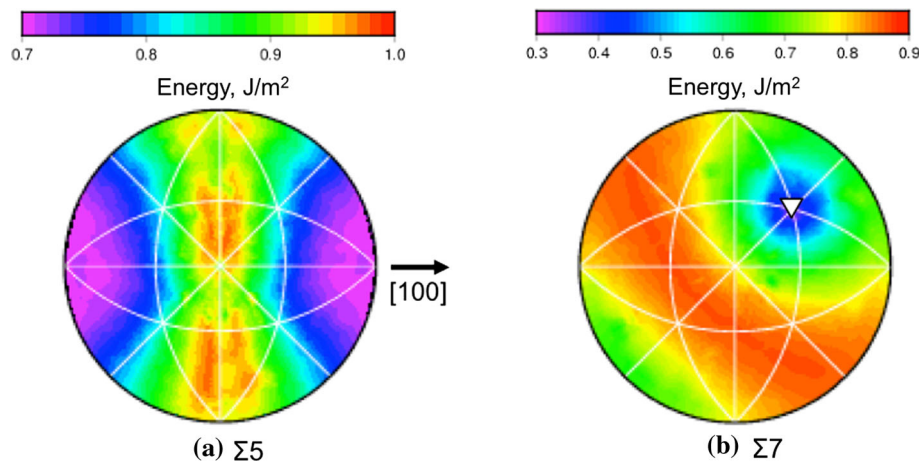
**Figure 5** Grain boundary plane distributions for the electroplated nanotwinned copper (a, d, g) and the coarse-grained copper reference sample (b, e, h) plotted in stereographic projection with units of multiples of a random distribution (MRD). The distributions of grain boundary energy in copper for  $\Sigma 3$ ,  $\Sigma 9$ , and  $\Sigma 11$  misorientations are derived from the grain boundary energy

function [54] and plotted in c, f, and i respectively. The [100], [010], and [001] directions are pointing along the horizontal, vertical, and perpendicular to the page, respectively. In a–c, the [111] misorientation axis is marked by a *triangle*, the misorientation axes in the other misorientations are in the plane of the page and marked by the *arrows*.

boundaries in the electroplated nanotwinned copper (46%) is significantly higher than that in the coarse-grained copper sample (27%).

The grain boundary plane and energy distributions are plotted for the most commonly observed misorientations ( $\Sigma 3$  at  $60^\circ$  around [111],  $\Sigma 9$  at  $38.9^\circ$  around [110], and  $\Sigma 11$  at  $50.5^\circ$  around [110]) in Fig. 5. Note that the GBCD was calculated with discrete  $10^\circ$  bins, and, for this reason, the  $\Sigma 27a$  boundary cannot be distinguished from the  $\Sigma 9$  boundary. The distributions are plotted as stereographic projections using

the bicrystal reference frame. For the  $\Sigma 3$  misorientation, the population distributions in nanotwinned copper (Fig. 5a) and in coarse-grained copper (Fig. 5b) reveal a very strong peak at the (111) twist boundary orientation. While these two distributions have a similar shape in which the maximum is located at the lowest boundary energy (the coherent twin boundary,  $0.02 \text{ J/m}^2$ ), the relative area for the coherent twin boundary in the electroplated nanotwinned copper (1800 MRD) is much greater than that in the coarse-grained copper (1200 MRD),



**Figure 6** The distributions of the grain boundary energy in copper for  $\Sigma 5$  and  $\Sigma 7$  misorientations are derived from the grain boundary energy function [54] and plotted in **a**, **b**, respectively. The [100], [010], and [001] directions are pointing along the horizontal,

vertical, and perpendicular to the page, respectively. For  $\Sigma 5$ , the [100] misorientation axis is in the plane of the page and marked by the arrows. For  $\Sigma 7$ , the [111] misorientation axis is marked by a triangle.

consistent with the higher concentration of coherent twin boundaries, noted above. The relative areas for grain boundaries at the  $\Sigma 9$  misorientation in the electroplated nanotwinned copper and in the coarse-grained copper have the maxima along the [110] zone, as shown in Fig. 5d, e, respectively. Because the maximum extends across many grain boundary plane orientations, there are combinations of asymmetric and symmetric tilt grain boundaries.

While the maximum of the grain boundary population distribution for the coarse-grained copper at the  $\Sigma 9$  misorientation (11 MRD) is located at the (1–14) symmetric tilt boundary, the peak maximum in the nanotwinned copper (20 MRD) is located at the asymmetric tilt boundary with (16,13,13)/(8,1,1). It should be noted that the boundary energy of this asymmetric tilt boundary ( $0.74 \text{ J/m}^2$ ) is comparable to the energy of the (1–14) symmetric tilt boundary ( $0.61 \text{ J/m}^2$ ), which is the lowest grain boundary energy at the  $\Sigma 9$  misorientation in Fig. 5f. Grain boundary population distributions at the  $\Sigma 11$  misorientation in the electroplated nanotwinned copper and in the coarse-grained copper as illustrated in Fig. 5g, h, respectively, are similar to the distributions for the  $\Sigma 9$  misorientation. The grain boundary energy distribution at the  $\Sigma 11$  misorientation in Fig. 5i is also similar to the distribution at the  $\Sigma 9$  misorientation. The lowest boundary energy at the  $\Sigma 11$  misorientation is the (1–13) symmetric tilt boundary ( $0.31 \text{ J/m}^2$ ), which is significantly lower in energy than the boundary energy of the (1–14)

symmetric tilt boundary ( $0.61 \text{ J/m}^2$ ) at the  $\Sigma 9$  misorientation. The boundary populations at the  $\Sigma 9$  and  $\Sigma 11$  misorientations in the electroplated nanotwinned copper are much more spread out along the [110] zone and greater than what is observed for the coarse-grained polycrystalline copper. The larger maxima in the electroplated nanotwinned copper are probably a direct result of the growth texture. With the dominant crystal orientation along [110], and the columnar grain shape, the grain boundary plane orientations are frequently perpendicular to [110], and this leads to the large population of [110] tilt boundaries.

The grain boundary energy distributions for the  $\Sigma 5$  and  $\Sigma 7$  boundaries are presented in Fig. 6. However, we observed so few of these boundaries in the specimens that the grain boundary plane distributions at these misorientations contribute so little significance to the overall distribution that we do not discuss them in more detail. The absence of  $\Sigma 7$  boundaries is unusual. The lowest energy  $\Sigma 7$  boundary ( $0.31 \text{ J/m}^2$ ) is comparable to the lowest energy  $\Sigma 11$  boundary ( $0.31 \text{ J/m}^2$ ) and almost half the lowest energy  $\Sigma 9$  boundary ( $0.61 \text{ J/m}^2$ ). Therefore, one would expect  $\Sigma 7$  boundaries to occur with approximately the same frequency as  $\Sigma 11$  boundaries and more than  $\Sigma 9$  boundaries, but this is not the case. In fact, the populations at the lowest energy  $\Sigma 7$  grain boundary, the (111) twist boundary, are only 0.25 and 0.4 MRD in the nanotwinned and coarse-grained copper, respectively.



## Discussion

In this study, the relative grain boundary areas in polycrystalline copper specimens fabricated by the electrodeposition technique and by rolling plus thermal annealing are measured and compared to the grain boundary energy. The microstructure of electroplated copper is dominated by the parameters of the deposition method, while the coarse-grained copper is dominated by recrystallization and grain growth. We find that the microstructure and texture of the electroplated copper are very different from those observed for the coarse-grained copper. Specifically, the electroplated copper has multiple parallel twin plates and strong directional growth with [110] fiber texture, while the coarse-grained copper has a weak texture with equiaxed grains as shown in Figs. 1 and 2.

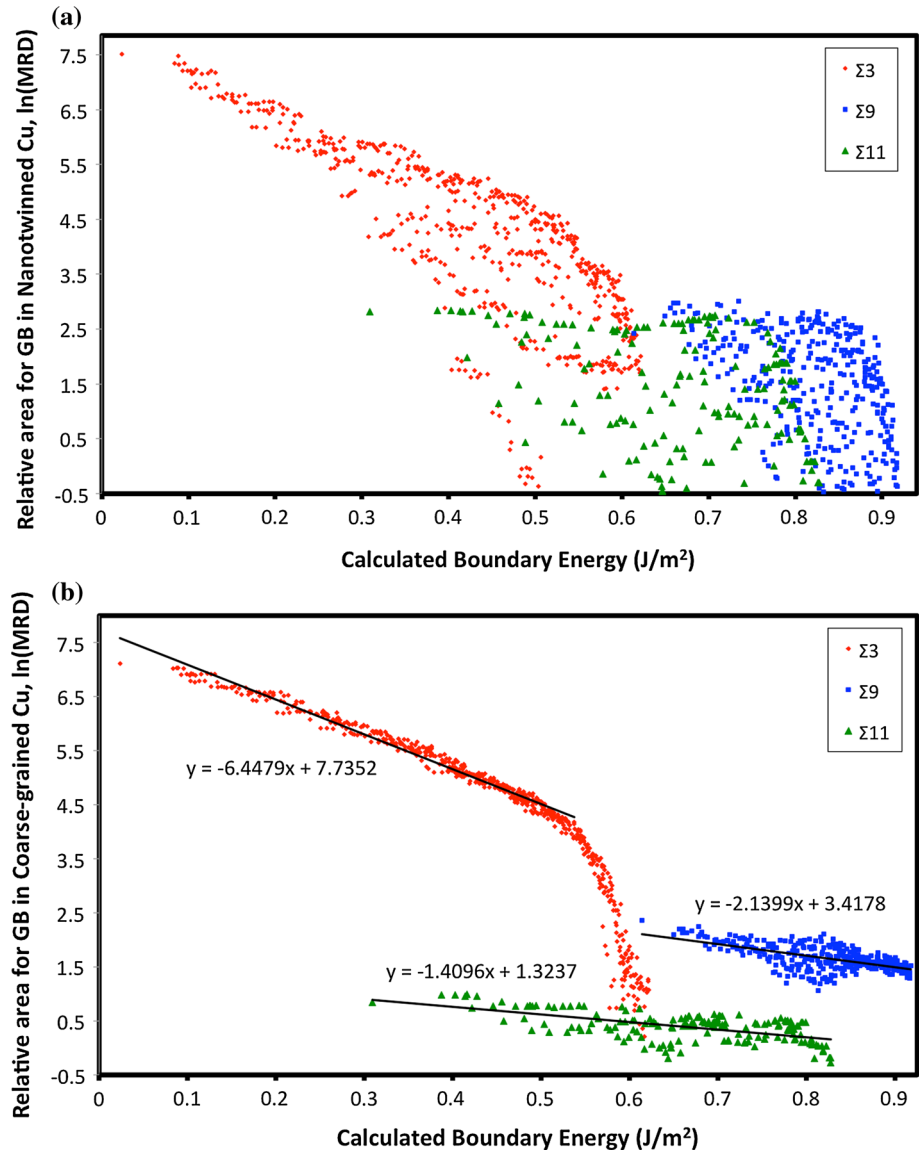
One of the most interesting results is the inverse relationship between the average grain boundary population and the average grain boundary energy in the electroplated and coarse-grained copper in Fig. 4a. While the average populations and the average energy in the electroplated nanotwinned and coarse-grained copper are inversely correlated, it is apparent that low boundary energies do not have high populations in every instance, as illustrated for the  $\Sigma 7$  boundary. Specifically, the (111) twist boundary at  $\Sigma 7$  ( $0.31 \text{ J/m}^2$ ), which is the lowest boundary energy at this misorientation, is less frequently observed than the (1–14) symmetric tilt boundary ( $0.61 \text{ J/m}^2$ ) at the  $\Sigma 9$  misorientation. To investigate the relationship between grain boundary population and grain boundary energy for individual boundaries, the grain boundary populations of the most highly populated grain boundaries ( $\Sigma 3$ ,  $\Sigma 9$ , and  $\Sigma 11$  misorientations) are plotted together with the grain boundary energies in Fig. 7. Comparisons between grain boundary population and energy for these misorientations (on a boundary-by-boundary basis) in the electroplated nanotwinned copper as shown in Fig. 7a indicate significant scatter and a weak correlation. The grain boundary network in the electroplated film does not reach the same distribution as in the coarse-grained copper that reveals a much stronger inverse correlation with the grain boundary energy, as shown in Fig. 7b. This is not surprising, based on the constraint imposed by the texture and grain shape. However, considering the weak correlation for individual boundaries, the strength of the average correlation shown in Fig. 4 is

surprising. Clearly, the point-by-point comparison is a much more rigorous test than the average comparison. It should be noted that the exact grain boundary distribution is probably sensitive to the precise processing parameters.

A previous study showed that the network of grain boundaries in the electrodeposited copper depends on the current characteristics during electrodeposition [68]. Therefore, the pulse forward period and the pulse reverse period could strongly influence the competitive processes of nucleation and grain growth in the electroplated film [69, 70]. During the pulse forward period, the high current density generates a large number of nuclei, which are likely to coalesce. Upon grain coalescence, two abutting grains are zippered together and form a grain boundary. The strain energy induced by the zipping increases the biaxial tensile stress of the electroplated films [71–73]. Recent studies on the in situ stress measurements of copper synthesized by the pulse electroplating showed a significant increase and decrease in the internal stress in every cycle of the pulse on- and pulse off-time periods [74, 75]. The cycle of stress generation and relaxation is similar to a recently suggested grain boundary engineering (GBE) scheme, which uses mechanical cycling at elevated temperature to increase the fraction of  $\Sigma 3$  boundaries in nanocrystalline Ni [76]. According to this approach, it is possible that the formation of the coherent twin boundary in the nanotwinned copper might be similar to the formation mechanism of the annealing twins, which results from the minimization of the interfacial energy and of the elastic strain energy [77, 78]. Because of the limited relaxation during the pulse off- or pulse reverse period, it is likely that the energy is not fully minimized and that residual strains remain in the electroplated nanotwinned copper.

The logarithms of the populations of grain boundaries with  $\Sigma 3$ ,  $\Sigma 9$ , and  $\Sigma 11$  misorientations in the coarse-grained copper in Fig. 7b are correlated to the grain boundary energy with correlation coefficients of  $-0.89$ ,  $-0.62$ , and  $-0.61$ , respectively. These correlation factors suggest that the Boltzmann distribution may be applicable to estimate the relative grain boundary population for each misorientation. Before beginning, we note that there is a dramatic change of slope for the high-energy, low population  $\Sigma 3$  boundaries in Fig. 7b. A similar trend between  $\Sigma 3$  grain boundary populations and energies was reported for aluminum, where the interface

**Figure 7** Relationship between grain boundary populations and grain boundary energies in copper for electroplated nanotwinned copper (a) and coarse-grained copper (b). Each point represents a grain boundary type, only  $\Sigma 3$ ,  $\Sigma 9$ , and  $\Sigma 11$  boundaries with populations  $>0.5$  MRD are plotted. The horizontal axis shows the boundary energies, while the vertical axis shows the logarithm of the relative grain boundary areas. The grain boundaries are separated into three categories,  $\Sigma 3$  (red diamonds),  $\Sigma 9$  (blue squares), and  $\Sigma 11$  (green triangles). The trend lines for the coarse-grained copper were determined from all data points in the plot at each misorientation, except for  $\Sigma 3$  where only boundaries with a population value above 0.5% of the coherent twin boundary population (1230 MRD) were considered.



populations were also determined stereologically [79], but not for nickel, where the interface populations were determined from 3D data [80]. Therefore, it is possible that the dramatic change in slope for the low population, high-energy boundaries is an artifact of the stereological interpretation of the data, and here we exclude this branch of the curve when calculating the correlation coefficient. Specifically, only such grain boundaries with a relative grain population greater than 0.5% of the coherent twin boundary population were fit to the Boltzmann distribution at  $\Sigma 3$ .

Assuming that the energy–population relationship is described by the Boltzmann distribution, the probability of observing a grain boundary with

energy ( $E_i$ ) compared to the total grain boundary population at the  $\Sigma 3$  misorientation ( $N_{\text{total}}^{\Sigma 3}$ ) is expressed by

$$P(E_i) = \frac{N(E_i)}{N_{\text{total}}^{\Sigma 3}} = \frac{e^{-E_i \alpha_{\Sigma 3} / k_B T}}{\zeta(\Sigma 3, T)} \tag{1}$$

$$N(E_i) = N_{\text{total}}^{\Sigma 3} \frac{e^{-E_i \alpha_{\Sigma 3} / k_B T}}{\zeta(\Sigma 3, T)}$$

To render the units correct in this formulation, we introduce  $\alpha_{\Sigma 3}$  as a unit area variable ( $\text{m}^2$ ) that should scale with the average length of a grain boundary with the  $\Sigma 3$  misorientation. We use  $k_B$  for the Boltzmann constant, and  $T$  is taken to be experimental temperature (573.5 K). However, the meaning of temperature in this case is not clear, as the events that

alter grain boundary populations are not analogous to the molecular processes usually described by the Boltzmann distribution. The partition function  $\xi(\Sigma 3, T)$  is the sum of all energy states ( $n$ ) at the  $\Sigma 3$  misorientation;  $\sum_i^n e^{-E_i \alpha_{\Sigma 3} / k_B T}$ . The logarithm of grain boundary population with  $E_i$  is given by

$$\ln N(E_i) = \frac{-E_i \alpha_{\Sigma 3}}{k_B T} + \ln \left( \frac{N_{\text{total}}^{\Sigma 3}}{\xi(\Sigma 3, T)} \right) \quad (2)$$

From Eq. (2), we see that the unit area variable ( $\alpha_{\Sigma 3} = 5.1 \times 10^{-20} \text{ m}^2$ ) is determined from the slope of the logarithm of the grain boundary population and the energy of the  $\Sigma 3$  misorientation in Fig. 7b. We find that the unit area variable for  $\Sigma 11$  ( $\alpha_{\Sigma 3} = 1.1 \times 10^{-20} \text{ m}^2$ ) is much smaller than  $\alpha_{\Sigma 3}$  and slightly smaller than the unit area variable for  $\Sigma 9$  ( $\alpha_{\Sigma 9} = 1.7 \times 10^{-20} \text{ m}^2$ ). The fact that the average length of a  $\Sigma 3$  boundary (8  $\mu\text{m}$ ) is larger than average lengths of  $\Sigma 9$  (5  $\mu\text{m}$ ) or  $\Sigma 11$  (5  $\mu\text{m}$ ) boundary suggests that these unit area variables are correlated to the average length for each misorientation. Based on the interpretation of Boltzmann-like distribution, relative grain boundary energies at each misorientation could be derived from relative grain boundary population of annealed polycrystalline copper.

The magnitudes of the unit area variables are also correlated to the grain boundary misorientation distribution. In other words, the larger the average grain boundary population, the greater is the slope of the distribution in Fig. 7b. The grain boundary misorientation distribution can be influenced by the fact that misorientation has to be conserved at the triple junction. According to the sigma combination rule,  $\Sigma a \times \Sigma b = m^2 \times \Sigma c$ , where  $\Sigma a$ ,  $\Sigma b$ , and  $\Sigma c$  are  $\Sigma$ -values of three grain boundaries at the triple junction and  $m$  can be any common divisor of  $\Sigma a$  and  $\Sigma b$  [4]. Because of this, multiple twinning ( $\Sigma 3^n$ ) influences the characteristics of triple junctions, the grain boundary misorientation distributions [21, 25, 81, 82], and the relative areas of grain boundaries [30, 83–85]. In the present datasets, the total number fractions of  $\Sigma 3$  boundaries at triple junctions in the nanotwinned copper (38%) and in the coarse-grained copper reference material (49%) are large. If the boundaries are randomly mixed at the triple junctions, the probability of forming a  $\Sigma 3$ – $\Sigma 3$ – $\Sigma 9$  triple junction is square of  $\Sigma 3$  grain boundary fraction,  $(\Sigma 3)^2$ . The probabilities of forming  $\Sigma 3$ – $\Sigma 3$ – $\Sigma 9$  grain boundaries in the nanotwinned copper (10%) and in the coarse-grained

copper (13%) are comparable with the measured concentrations of these junctions (nanotwinned copper = 10% and coarse-grained copper = 16%). Therefore, the  $\Sigma 3$ – $\Sigma 3$ – $\Sigma 9$  junctions in nanotwinned and coarse-grained copper are likely to result from random mixing of the  $\Sigma 3$  boundaries and the crystallographic constraint at the triple junction. The number fractions of  $\Sigma 3$ – $\Sigma 3$ – $\Sigma 9$  junctions are much larger than the length fraction of  $\Sigma 9$  boundaries. This is because the  $\Sigma 9$  boundaries are typically found as short segments in the network connecting  $\Sigma 3$  boundaries. In contrast,  $\Sigma 3$  boundaries typically traverse entire grain diameters or form sinuous structures within grains, so that each  $\Sigma 3$  boundary is much longer than typical  $\Sigma 9$  boundaries. The increase in the population of coherent twins and grain boundaries terminated on {111} planes not only enhances the population of  $\Sigma 9$  grain boundaries but also asymmetric tilt boundaries with  $\langle 110 \rangle$  misorientations [19, 30, 32].

Our results indicate that while the misorientation specified by the three degrees of freedom is constrained by the geometry of the boundary, the boundary plane distribution is strongly influenced by the grain boundary energy. It should be noted that in the case of coarse-grained copper, a grain boundary can relax to the most energetically favorable grain boundary plane at a fixed misorientation [86–88]. The multiple twinning and the geometric constraint at the triple junction significantly influence the topological network and the relative areas of  $\Sigma 3^n$  grain boundary in both samples. While there was on average enough grain growth in the electroplated specimen to reach the same distribution as in the coarse-grained specimen, as shown in Fig. 4a, it was not sufficient to achieve to the most energetically favorable grain boundary plane at a fixed misorientation. This results in the significant scatter and a weak correlation between the grain boundary populations and grain boundary energies in Fig. 7a. Therefore, the grain boundary character distribution (GBCD) of nanotwinned copper is thermally unstable and it would be expected to change during high-temperature annealing.

Because electroplating parameters have a significant effect on grain morphology, crystallographic texture, and multiple twinning mechanisms [39, 69, 89–96], it is possible to tailor the grain boundary character distribution (GBCD) of electroplated nanotwinned copper by varying voltage,

current density, duty cycle, and the chemistry of the plating bath. It was reported that the crystallographic textures of electroplated copper were changed from [111] to [100] and [101] when the duty cycles of pulsed reverse electrodeposition were reduced [92]. Because the nucleation of nanotwinned lamellae preferentially occurs in the [111] growth direction compared with the [100] and [101] directions [97], electroplated copper having strong [111] texture is expected to have a high density of  $\Sigma 3$  coherent twin boundaries and much finer nanotwinned lamellae. Therefore, electroplated nanotwinned copper with strong [111] texture could be potentially used as interconnects for microelectronic devices because of its excellent mechanical properties, low electrical resistivity, and high electromigration resistance [92, 98, 99]. Recently, it was demonstrated that the nanotwinned lamellae in electroplated copper with strong [111] texture were thermally stable after annealing at 300 °C [100]. While the reason for the thermal stability of the nanotwinned lamellae is not clear, the thermal stability might be related to the grain boundary character distribution (GBCD). It is therefore worth investigating how the GBCD of electroplated nanotwinned copper with strong [111] texture and the grain boundary energy are correlated. Knowledge of the energy population relationship would benefit the design of thermally stable nanocrystalline materials.

## Conclusions

The grain boundary character distribution (GBCD) of electroplated nanotwinned copper was compared to the GBCD of a coarse-grained copper reference polycrystal and to grain boundary energies extrapolated from simulated values. While the microstructure of the electroplated nanotwinned copper is much different from the coarse-grained copper, the distribution of relative grain boundary areas for the nanotwinned copper is, on average, comparable to the distribution for coarse-grained copper. We demonstrate that there is a single strong inverse correlation between the grain boundary energy and grain boundary population when groups of boundaries in the same energy range are averaged. When individual boundaries are compared in a point-by-point fashion, a strong inverse correlation is also found, but the slope of the correlation is not the same at all misorientations. In addition to the grain boundary

energy, the columnar grain structure, the texture, and the geometric constraints at the triple junctions influenced the grain boundary networks and GBCD of the polycrystalline copper specimens. The findings presented here may enhance the application of grain boundary engineering in electrodeposited copper used in microelectronic interconnect technology.

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## Compliance with ethical standards

**Conflict of interest** The authors declare that there is no conflict of interest.

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